



BSI Standards Publication

Guidelines for measuring the threshold voltage (V_T) of SiC MOSFETs

National foreword

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The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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Published by BSI Standards Limited 2025

ISBN 978 0 539 27269 7

ICS 31.080.30

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 30 April 2025.

Amendments/corrigenda issued since publication

Date	Text affected
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